

# Search Notes



Application/Control No.

10/775,473

Examiner

Mark H. Paschall

Applicant(s)/Patent under Reexamination

CHEN ET AL.

Art Unit

3742

## SEARCHED

Class	Subclass	Date	Examiner
219	497 505 790	8-3-05	m
	499 201-205		
73	51.05		
	31.06 23.2		
	23.32		
374	144, 1		
about		11/27/05	m
data			

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
cell aban			
219	490 497	11/27/05	m P

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Est enclosure	8/3/05	z
update Easlo	11/27/05	m